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Measurement method of a half-wavelength voltage for Mach-Zehnder optical modulators in wireless communication and broadcasting systems

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CONTENTS

FOREWORD.....	4
INTRODUCTION.....	5
1 Scope.....	6
2 Normative references	6
3 Terms, definitions and acronyms	6
3.1 Terms and definitions	6
4 Electro-optic material based Mach-Zehnder optical modulator	8
4.1 Type.....	8
4.2 Structure	8
4.3 Requirements for Mach-Zehnder optical modulators	8
5 Sampling.....	9
5.1 Sampling	9
5.2 Sampling frequency.....	9
6 Measurement method of half wavelength voltage.....	9
6.1 Circuit diagram	9
6.2 Circuit description and requirement	9
6.3 Measurement condition	10
6.4 Principle of measurement method	10
6.5 Measurement procedure.....	13
Annex A (normative) Conventional Measurement method of Optical Modulation Index	17
Annex B (informative) Calculation method of intermodulation distortions from driving voltages and half-wavelength voltage for Mach-Zehnder optical modulator	19
Annex C (informative) Characteristics of Mach-Zehnder optical modulator	27
Annex D (informative) Points to consider for measurement	29
Bibliography.....	35
Figure 1 – A transfer curve of a Mach-Zehnder optical modulator	7
Figure 2	8
Figure 3 – Circuit diagram.....	9
Figure 4	11
Figure 5 – The schematic block diagram of the measurement setup.....	12
Figure 6 – Driving voltage measurement setup	14
Figure 7	15
Figure 8 a) – The amplitude of the optical signal is almost zero	16
Figure 8 b) – The optical signal is modulated in phase with S2 element	16
Figure 8 c) – The optical signal is modulated in opposite phase with S2 element	16
Figure A.1.....	17
Figure A.2.....	18
Figure B.1 Mach-Zehnder interferometer type optical modulator	19
Figure B.2 – Quadrature points of a transfer curve for a Mach-Zehnder optical modulator	23

Figure B.2 – Dependency of IM2 on NOMI and Bias voltage of a Mach-Zehnder optical modulator 24

Figure B.4 – Relation between IM3 and OMI of a Mach-Zehnder optical modulator 24

Figure B.5..... 25

Figure B.6 – IMD2 and IMD3..... 26

Figure D.1 – Errors of half-wavelength voltage measurements caused by limitations from the resolution of RF power supply 31

Figure D.2 – Relative errors of half-wavelength voltage measurement caused by limitations from the resolution of RF power 32

Figure D.3 – Relation between NOMI and IM3 for the Mach-Zehnder modulator (sample #1) 33

Figure D.4 – Relation between NOMI and IM3 for the Mach-Zehnder modulator (sample #2) 33

Figure D.5 – Relation between NOMI and IM2 for the Mach-Zehnder modulator (sample #1) 34

Table 1 – Acronyms 7

Table C.1 27

Table C.2 28

Table D.1 29

Table D.2 – Measurement results of half-wave voltages for Mach-Zehnder modulators 32

INTERNATIONAL ELECTROTECHNICAL COMMISSION

**MEASUREMENT METHOD OF A HALF-WAVELENGTH VOLTAGE
FOR MACH-ZEHNDER OPTICAL MODULATORS IN WIRELESS
COMMUNICATION AND BROADCASTING SYSTEMS**

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Following publication of this PAS, which is a pre-standard publication, the technical committee or subcommittee concerned may transform it into an International Standard.

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INTRODUCTION

A variety of microwave-photonic devices are used in wireless communication and broadcasting systems. An optical modulator is an interface which converts an electronic signal into an optical signal. In the field of optical fibre communication systems, the IEC 62007 series "Semiconductor optoelectronic devices for fibre optic system applications" has been published. In the field of wireless systems, specifications of inter-modulation and composite distortion of modulators have been an important issue and have typically been negotiated between users and suppliers. During an International Meeting on Microwave Photonics, a proposal was announced to address standardizations for key-devices for Radio over Fibre (RoF) systems.

The RoF system is comprised mainly of two parts; one is the RF to photonic converter (E/O), and the other is photonic to RF converter (O/E). Radio waves are converted into an optical signal at E/O, and the signal is transferred into the optical fibre, and then the radio waves are regenerated at O/E. The nonlinear distortion characteristics of both E/O and O/E are important for the performance of the system. Semiconductor photodiodes are commonly used for O/E. Several types of optical modulator are used for E/O, such as Mach-Zehnder modulators, electro-absorption modulators and directly modulated LDs.

This PAS has been prepared in order to provide industry standard measurement methods for evaluating electro-optic material based Mach-Zehnder optical modulators to be used in wireless communication and broadcasting systems. When the optical modulation index (OMI) is calculated from the half-wavelength voltage measurement results, the intermodulation distortion of the Mach-Zehnder optical modulator can be obtained. In this PAS, the measurement method of the half-wavelength voltage for Mach-Zehnder optical modulators is described. The details of calculations of the second order intermodulation distortion (IM2) and the third order intermodulation distortion (IM3) are described in Annex B.

MEASUREMENT METHOD OF A HALF-WAVELENGTH VOLTAGE FOR MACH-ZEHNDER OPTICAL MODULATORS IN WIRELESS COMMUNICATION AND BROADCASTING SYSTEMS

1 Scope

This PAS gives a measurement method of half-wavelength voltage applicable to Mach-Zehnder optical modulators in wireless communication and broadcasting systems. In addition, this method is also effective for the estimation of the intermodulation distortion of Mach-Zehnder optical modulators.

- Frequency range: 10 MHz to 30 GHz.
- Wavelength band: 0,8 μm , 1,0 μm , 1,3 μm and 1,5 μm .
- Electro-optic material based Mach-Zehnder optical modulators and their modules.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 62007-1, *Semiconductor optoelectronic devices for fibre optic system applications - Part 1: Specification template for essential ratings and characteristics*

IEC 62007-2 *Semiconductor optoelectronic devices for fibre optic system applications - Part 2: Measuring methods*